

<b>Notice of References Cited</b>	Application/Control No. 10/561,680		Applicant(s)/Patent Under Reexamination OHNO ET AL.	
	Examiner KARUNA P. REDDY		Art Unit 1796	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,135,518 B2	11-2006	Bandou et al.	524/445
	B	US-			
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	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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#### NON-PATENT DOCUMENTS

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	U	Abstract in English; Nakagawa et al; 05-2000.
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	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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